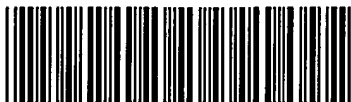


**Search Notes**

Application/Control No.

10/633,162

Examiner

Mark K. Han

Applicant(s)/Patent under  
Reexamination

WAKABAYASHI ET AL.

Art Unit

3767

**SEARCHED**

Class	Subclass	Date	Examiner
604	93.01	4/3/2006	mah
	131		
	154		
	155		
✓	187		
128	dig. 1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	4/3/2006	mah